	Application No.	Applicant(s)
	10/650,062	NATORI, YASUAKI
Notice of Allowability	Examiner	Art Unit
	Faye Boosalis	2884
The MAILING DATE of this communication apper All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	ears on the cover sheet with the co (OR REMAINS) CLOSED in this ap) or other appropriate communicatio IGHTS. This application is subject to	pplication. If not included on will be mailed in due course. THIS
1. A This communication is responsive to submission of 10 Nov	<u>/ember 2006</u> .	
2. The allowed claim(s) is/are <u>6,12-14,16 and 19-26</u> .		
3. Acknowledgment is made of a claim for foreign priority una) Ali b) Some* c) None of the:		
 Certified copies of the priority documents have been received. Certified copies of the priority documents have been received in Application No 		
 Certified copies of the priority documents have been received in Application No Copies of the certified copies of the priority documents have been received in this national stage application from the 		
3. பு Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).		
* Certified copies not received:		
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Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		/ complying with the requirements
4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give		
5. CORRECTED DRAWINGS (as "replacement sheets") mus	st be submitted.	·
(a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached		
1) hereto or 2) to Paper No./Mail Date	,	
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date		
Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in t		
6. DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT	sit of BIOLOGICAL MATERIAL FOR THE DEPOSIT OF BIOLOGIC	must be submitted. Note the CAL MATERIAL.
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Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	□ Nation of Informal /	To the American
 □ Notice of References Cited (P10-892) □ Notice of Draftperson's Patent Drawing Review (PT0-948) 	 5. ☐ Notice of Informal F 6. ☐ Interview Summary 	
	Paper No./Mail Da	ate
Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date	7. Examiner's Amend	Iment/Comment
Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. X Examiner's Statem	nent of Reasons for Allowance
or biological Material	9. Other	.
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EXAMINER'S STATEMENT OF REASONS FOR ALLOWANCE

Comment on Submissions

1. This communication is responsive to submissions 10 November 2006.

2. Claims 1-5, 7-11, 15 and 17-18 are cancelled.

Allowable Subject Matter

3. Claims 6, 12-14, 16 and 19-21 were previously allowed.

4. Claims 6, 12-14, 16, 19-26 are allowed.

5. The following is an examiner's statement of reasons for allowance:

Regarding independent claim 6, the prior art does not disclose or fairly suggest a laser scanning microscope comprising: a second optical scanning system wherein the second optical scanning system is attachable and detachable with respect to a main body of the laser scanning microscope that includes the first optical scanning system.

The examiner notes that while it is known in the art of a laser scanning microscope comprising: a first optical scanning system (1) which scans a first laser light (100) for observing a sample on the sample (110); a first light branch device (101) which separates a light from a sample from an optical path of the first laser light (100); at least one photodetector (115) which detects the light from the sample from an optical path of the first light branch device; a second optical scanning system (3) which irradiates a specific portion on the sample with a second laser light for stimulating or operating the sample; and a wavelength selection device (112) which is disposed between the first light branch device and the photodetector (115) and which has a first function of transmitting a desired observation light and a second function for limiting transmission

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of the second laser light (2) (see for example *Kashima et al -- US 6,094,300 A –* Fig. 1 and col. 7, lines 4-27, col. 8, lines 45-50 and col. 9, lines 38-58), the prior art does not suggest an attachable and detachable second optical scanning system of a laser scanning microscope.

Regarding independent claim 12, the prior art does not disclose or fairly suggest a laser scanning microscope wherein the wavelength selection device comprises: at least one second interference filter which performs the second function.

The examiner notes that while it is known in the art of a laser scanning microscope comprising: a first optical scanning system (1) which scans a first laser light (100) for observing a sample on the sample (110); a first light branch device (101) which separates a light from a sample from an optical path of the first laser light (100); at least one photodetector (115) which detects the light from the sample from an optical path of the first light branch device; a second optical scanning system (3) which irradiates a specific portion on the sample with a second laser light for stimulating or operating the sample; and a wavelength selection device (112) which is disposed between the first light branch device and the photodetector (115) and which has a first function of transmitting a desired observation light and a second function for limiting transmission of the second laser light (2) (see for example *Kashima et al -- US 6,094,300 A - Fig.* 1 and col. 7, lines 4-27, col. 8, lines 45-50 and col. 9, lines 38-58); and wherein the wavelength selection device comprises an interference filter (see for example *Kashima et al -- US 6,094,300 A - Fig.* 1 and col. 7, lines 28-39 and col. 8, lines 35-50), the prior

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art does not suggest wherein a wavelength selection device comprises at least one

second interference filter.

The remaining 13-14, 16, 19-26 are allowable based on their dependency.

Conclusion

6. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Faye Boosalis whose telephone number is 571-272-

2447. The examiner can normally be reached on Monday thru Friday from 7:00 AM to

3:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Dave Porta can be reached on 571-272-2444. The fax phone number for

the organization where this application or proceeding is assigned is 571-273-8300.

7. Information regarding the status of an application may be obtained from the

Patent Application Information Retrieval (PAIR) system. Status information for

published applications may be obtained from either Private PAIR or Public PAIR.

Status information for unpublished applications is available through Private PAIR only.

For more information about the PAIR system, see http://pair-direct.uspto.gov. Should

you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

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DAVID PORTA

SUPERVISORY PATERIT EXAM

TEUM LU.